PicoCube™ XY Stage and XYZ Stage for AFM

High-Dynamics Nanoscanner for Scanning Probe Microscopy

P-363.2CD and .3CD (background) PicoCube™, high-performance piezo positioning- and scanning systems or AFM/STM and nanomanipulation. Smart media card for size comparison

- **Ultra-High-Performance Closed-Loop Scanner for AFM/SPM**
- **Compact Manipulation Tool for Bio/Nanotechnology**
- **Resonant Frequency 9.8 kHz**
- **Capacitive Sensors for Highest Accuracy**
- **Parallel-Motion Metrology for Automated Compensation of Guiding Errors**
- **50 Picometer Resolution**
- **5 x 5 x 5 µm Travel Range**
- **Vacuum-Compatible Versions**

The P-363 PicoCube™ XY/XYZ is an ultra-high-performance closed-loop piezo scanning system. Designed for AFM, SPM and nanomanipulation applications, it combines an ultra-low inertia, high-speed XY/XYZ piezo scanner with non-contact, direct-measuring, parallel-metrology capacitive feedback capable of 50 picometers resolution. On top of being extremely precise, the PicoCube™ system is also very small and rugged. Measuring only 30 x 30 x 40 mm (with removable top plate, 30 x 30 x 28 mm for XY version), it is easy to integrate in any scanning apparatus.

Application Examples

- Scanning microscopy (SPM)
- Biotechnology
- Micromanipulation
- Nanopositioning
- Nano-imprinting
- Nanometrology
- Nanolithography

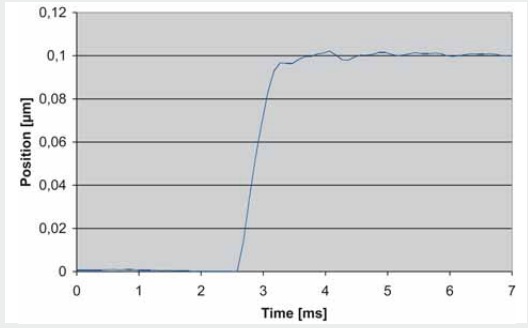
SPM, AFM, STM, Nanolithography, Nanoimprinting, Nanometrology

The PicoCube™ was specifically developed to overcome the limitations of the open-loop scanners currently available for SPM, AFM and STM. In addition to these applications, the PicoCube™ is also the ideal scanning and manipulation tool for nanoimprinting, nanolithography, ultra-high-resolution, near-field, scanning optical microscopy and nanosurface-metrology applications.

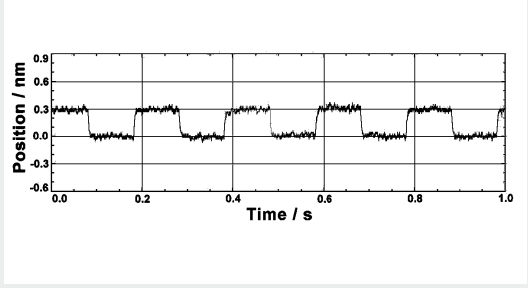
Higher Precision Through Parallel-Motion Metrology w/ Capacitive Sensors

The PicoCube™ is based on a proprietary, ultra-fast, piezo-driven scanner design equipped with direct-measuring, capacitive position sensors (parallel metrology). Unlike conventional sensors, they measure the actual distance between the fixed frame and the moving part of the stage. This results in higher-motion linearity, long-term stability, phase fidelity, and—because external disturbances are seen by the sensor immediately—a stiffer, faster-responding servo-loop.

Multi-axis nanopositioning systems equipped with parallel direct metrology are able to measure the platform position in all degrees of freedom against one fixed reference. In such systems, undesirable motion from one actuator in the direction of another (cross-talk) is detected immediately and act ively compensated by the servo-loops. This Active Trajectory Control Concept can keep deviation from a trajectory to under a few nanometers, even in dynamic operation.



The P-363 settles to within 1 nm in 1 ms (100 nm step, X and Y motion; faster response in Z)



300 picometer steps (0.3 nm) performed with the P-363, measured with an external high-resolution, capacitive measurement system

Nanometer Accuracy in 1 Millisecond with 30-Picometer Resolution

PicoCube™ systems provide resolution of 30 picometers and below. The ultra-fast XY/XYZ piezo drives offer resonant frequencies of 9.8 kHz in Z and >3 kHz in X and Y! The high resonant frequency and high-bandwidth capacitive feed back allow step and settle to 1% accuracy in as little as one millisecond.

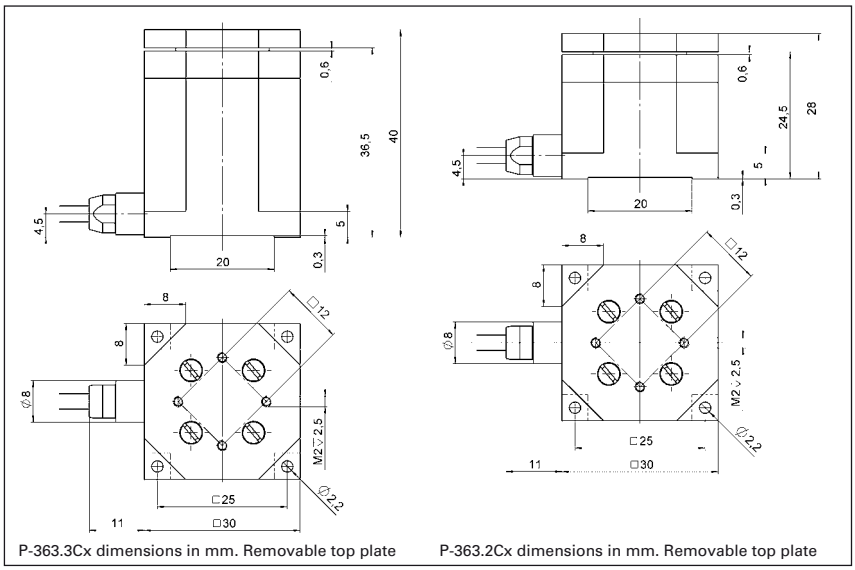
Rugged Design

In spite of its ability to move and position on an atomic scale, the PicoCube™ boasts a rugged design for real-world applications. For extra-high stability and reduced mass, the body is precision machined from heat-treated and stress-relieved titanium. The sophisticated frictionless design also ensures that the (moving) top plate protects the internal actuator/sensor unit from contamination.

Controller

For dynamic scanning opera - tion the E-725.3CM high-power digital controller offers advanced linearization algorithms for sub-nanometer precision (see p. 2-126).

Alternatively the analog E-536 PicoCube™ controller (see p. 2-134) comes in different versions optimized for resolution or power . An optional E-517 24-bit interface module is also available (see p. 2-156).



P-363.3Cx dimensions in mm. Removable top plate

P-363.2Cx dimensions in mm. Removable top plate

Technical Data

Model	P-363.3CD	P-363.2CD	Units
Active axes	X, Y, Z	X, Y	
Motion and positioning			
Integrated sensor	Capacitive	Capacitive	
Open-loop travel X, Y, -250 to +250 V	±3	±3	µm
Open-loop travel, -250 to +250 V	±2.7	–	µm
Closed-loop travel X, Y	±2.5	±2.5	µm
Closed-loop travel	±2.5	–	µm
Open-loop resolution	0.03*	0.03*	nm
Closed-loop resolution	0.1	0.1nm	
Linearity	0.05	0.05	%
Repeatability	1**	1**	nm
Pitch / yaw in X, Y	0.5	0.5	µrad
Runout X, Y (Z motion)	0.2	–	µrad
Straightness in X, Y	3	3	nm
Flatness in X, Y	<10	<10	nm
Crosstalk X, Y (Z motion)	5	–	nm
Mechanical properties			
Unloaded resonant frequency in X, Y	3.1	4.2	kHz
Unloaded resonant frequency (Z)	9.8	–	kHz
Resonant frequency in X, Y	1.5 (20 g)	2.1 (20 g)	kHz
Load capacity	10	10	N
Ceramic type	PICA™, PICA™ Shear	PICA™ Shear	
Miscellaneous			
Operating temperature range	-20 to 80	-20 to 80	°C
Material	Titanium	Titanium	
Dimensions	30 x 30 x 40	30 x 30 x 28	mm
Mass	225	190	g
Cable length	1.5	1.5	m
Sensor / voltage connection***	Sub-D connector PicoCube™	Sub-D connector PicoCube™	
Recommended controller	E-536 PicoCube™ Controller	E-536 PicoCube™ Controller	

Resolution of PI Piezo Nanopositioners is not limited by friction or stiction. V alue given is noise equivalent motion with E-536 controller (p. 2-134)

*With E-536.3xH Controller

**for 10% travel in Z; 50 nm for 100 % travel in Z

***P-363.xCL versions with LEMO connectors

System properties

System configuration	P-363.3CD (Z-axis) with 20 g load and E-536 servo controller
Settling time	(10 % step width) 1 ms